PSMN8R0-30YL

N-channel 8.3 m Ω 30 V TrenchMOS logic level FET in LFPAK Rev. 2 — 16 May 2011 Product data she

Product data sheet

Product profile 1.

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference data

Table 1.	Quick reference de	ata				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	30	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	-	-	62	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	56	W
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	6.9	8.3	mΩ
Dynamic	characteristics					
Q_{GD}	gate-drain charge	V_{GS} = 10 V; I_D = 45 A; V_{DS} = 15 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	4	-	nC
Q _{G(tot)}	total gate charge	$V_{GS} = 4.5 \text{ V}; I_D = 45 \text{ A}; V_{DS} = 15 \text{ V};$ see <u>Figure 14</u> ; see <u>Figure 15</u>	-	9	-	nC
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 62 A; V_{sup} ≤ 30 V; R_{GS} = 50 Ω; unclamped	-	-	21	mJ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		
4	G	gate	=	u———
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK; Power-SO8)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN8R0-30YL	LFPAK; Power-SO8	plastic single-ended surface-mounted package; 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	30	V
V_{DSM}	peak drain-source voltage	$t_p \le 25 \text{ ns}$; $f \le 500 \text{ kHz}$; $E_{DS(AL)} \le 70 \text{ nJ}$; pulsed	-	35	V
V_{DGR}	drain-gate voltage	T_j ≥ 25 °C; T_j ≤ 175 °C; R_{GS} = 20 kΩ	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	44	Α
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	-	62	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \mu s$; $T_{mb} = 25 \text{ °C}$; see Figure 3	-	247	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	56	W
T _{stg}	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-drai	n diode				
Is	source current	T _{mb} = 25 °C	-	62	Α
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$	-	247	Α
Avalanche r	uggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 62 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω ; unclamped	-	21	mJ

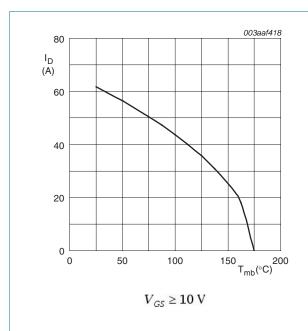


Fig 1. Continuous drain current as a function of mounting base temperature

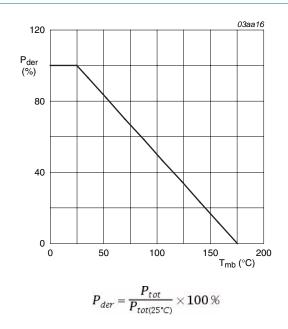
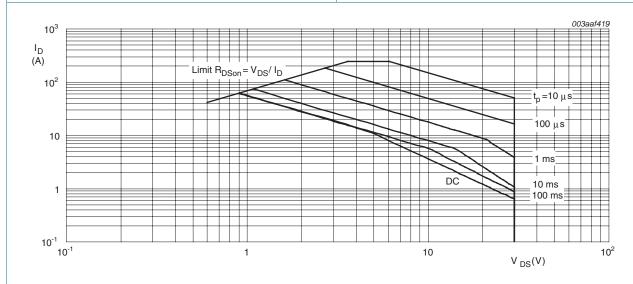


Fig 2. Normalized total power dissipation as a function of mounting base temperature



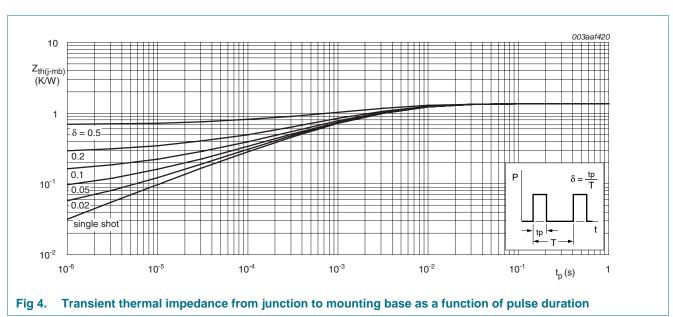
 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 4	-	1.35	2.7	K/W



6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics					
V _{(BR)DSS}	drain-source breakdown	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 25 \text{ °C}$; see <u>Figure 11</u> ; see <u>Figure 12</u>	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 150$ °C; see Figure 12	0.5	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 12	-	-	2.55	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I_{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
R_{DSon}	drain-source on-state	V_{GS} = 4.5 V; I_D = 15 A; T_j = 25 °C	-	10.4	12.2	$m\Omega$
	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see <u>Figure 13</u>	-	-	15	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C	-	6.9	8.3	mΩ
R_G	gate resistance	f = 1 MHz	-	2.03	-	Ω
Dynamic ch	aracteristics					
Q _{G(tot)} t	total gate charge	$I_D = 45 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 14; see Figure 15	-	9	-	nC
		$I_D = 45 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 14; see Figure 15	-	18.3	-	nC
		I _D = 0 A; V _{DS} = 0 V; V _{GS} = 10 V	-	16.1	-	nC
Q_{GS}	gate-source charge	$I_D = 45 \text{ A}$; $V_{DS} = 15 \text{ V}$; $V_{GS} = 10 \text{ V}$;	-	2.7	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	see <u>Figure 14</u> ; see <u>Figure 15</u>	-	1.5	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	1.2	-	nC
Q_{GD}	gate-drain charge		-	4	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V _{DS} = 15 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	3.2	-	V
C _{iss}	input capacitance	$V_{DS} = 15 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	1005	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 17</u>	-	200	-	pF
C _{rss}	reverse transfer capacitance		-	102	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 15 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	15	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	29	-	ns
$t_{d(off)}$	turn-off delay time		-	21	-	ns
t _f	fall time	V_{DS} = 15 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V; $R_{G(ext)}$ = 4.7 Ω	-	8	-	ns

Table 6. Characteristics ...continued

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drai	n diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 16	-	0.9	1.2	V
t _{rr}	reverse recovery time	$I_S = 15 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$;	-	34	-	ns
Qr	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 15 \text{ V}$	-	30	-	nC

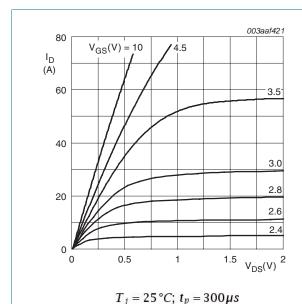


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

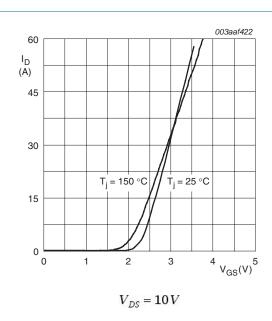


Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

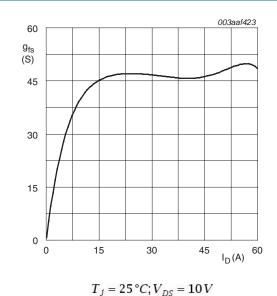


Fig 7. Forward transconductance as a function of drain current; typical values

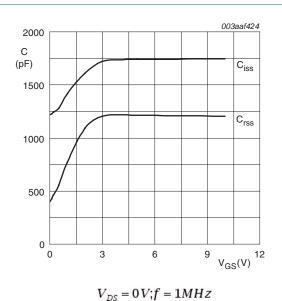


Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

PSMN8R0-30YL

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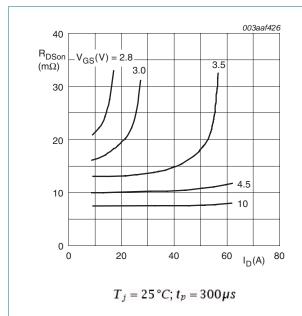
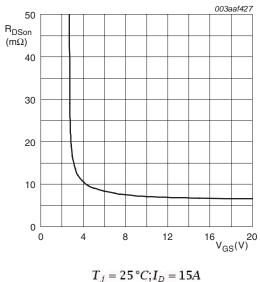


Fig 9. of drain current; typical values



Drain-source on-state resistance as a function Fig 10. Drain-source on-state resistance as a function of gate-source voltage; typical values

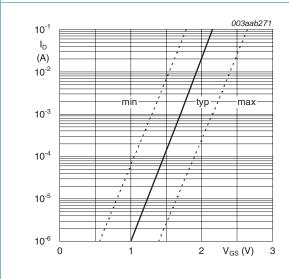
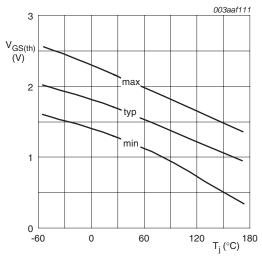


Fig 11. Sub-threshold drain current as a function of gate-source voltage

 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$



 $I_D = 1mA; V_{DS} = V_{GS}$

Fig 12. Gate-source threshold voltage as a function of junction temperature

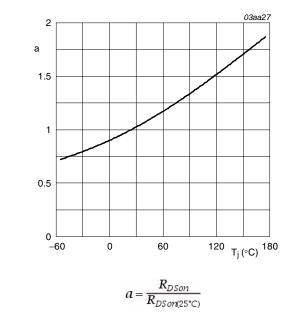


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

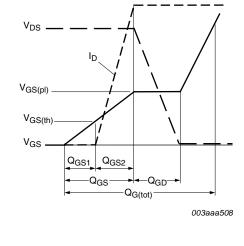


Fig 14. Gate charge waveform definitions

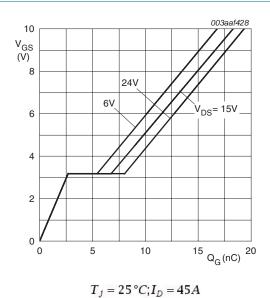


Fig 15. Gate-source voltage as a function of gate charge; typical values

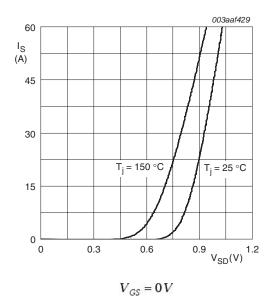


Fig 16. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

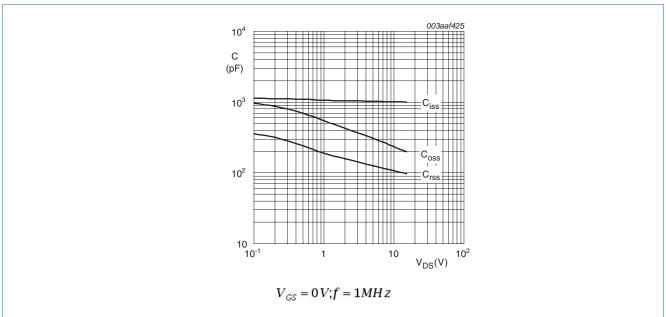
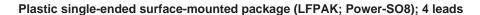
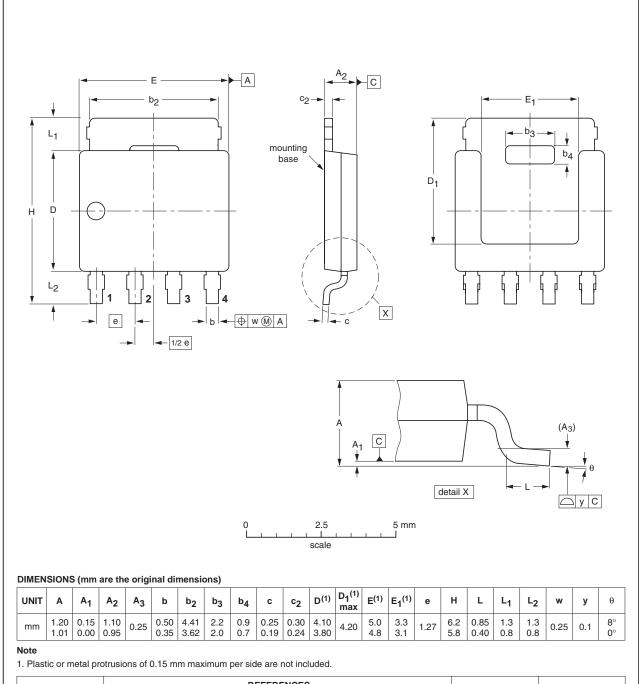


Fig 17. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

7. Package outline



SOT669



OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT669		MO-235			06-03-16 11-03-25

Fig 18. Package outline SOT669 (LFPAK; Power-SO8)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN8R0-30YL v.2	20110516	Product data sheet	-	PSMN8R0-30YL v.1
Modifications:	 Various change 	s to content.		
PSMN8R0-30YL v.1	20110217	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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N-channel 8.3 mΩ 30 V TrenchMOS logic level FET in LFPAK

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